Search Notes					

Application/Control No.	Applicant(s)/Patent under Reexamination	-
09/886,741	CHAN ET AL.	
Examiner	Art Unit	
Chris C. Chu	2815	

	SEARCHED			
Class	Subclass	Date	Examiner	
257	723, 724, 796, 787, 784 & 685	1/19/2006	C.C.	
257	780 & 778	1/19/2006	C.C.	
257	731 & 706	1/19/2006	C.C.	

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
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SEARCH NOT (INCLUDING SEARCH		
	DATE	EXMR
Searched in US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; and IBM_TDB;	11/19/2006	C.C.